PLL-INTER VIF/SIF

DESCRIPTION

M52768FP is a semiconductor integrated circuit consisting of VIF/SIF signal processing for CTVs and VCRs. M52768FP provide low cost and high performance system with the coil-less AFT.

FEATURES

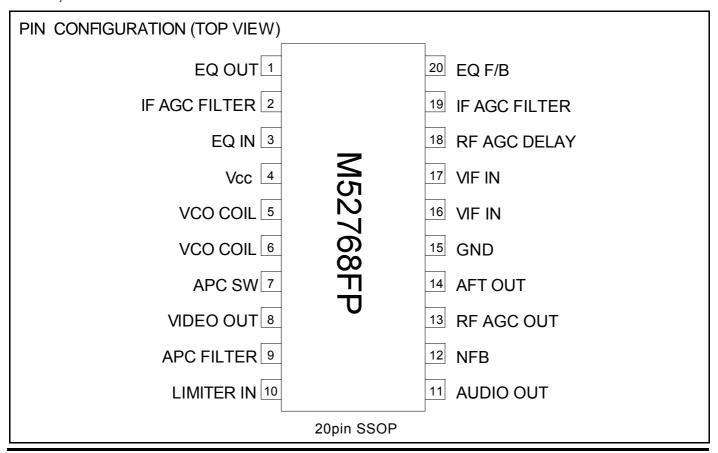
- ■Inter carrier /NTSC only(4.5MHz)
- Coil-less AFT.
- ■PLL FM demodulation for Audio. No external parts and adjustment.
- ■Video output is 2.0Vp-p through EQ AMP.
- ■Easy to add Buzz canceler.
- ■Hi speed IF AGC.
- ■Improve over modulation characteristics.

RECOMMENDED OPERATING CONDITIONS

Supply Voltage Range (Vcc) • • • • • • 4.5 to 5.5 V
Rated Supply Voltage (Vcc) • • • • • • 5.0 V

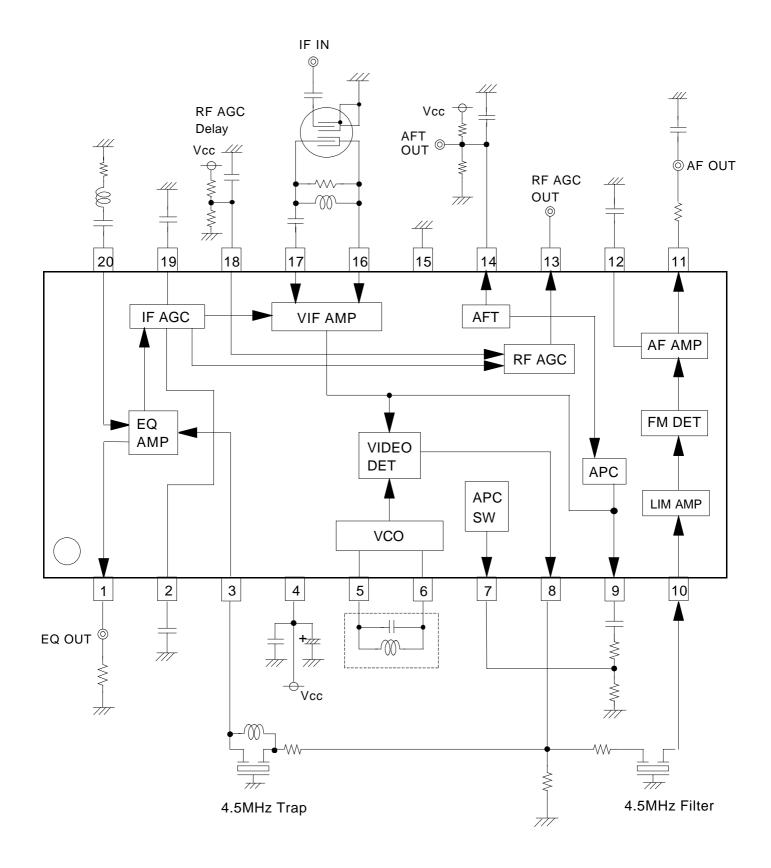
APPLICATION

TV,VTR





BLOCK DIAGRAM and PERIPHERAL CIRCUIT

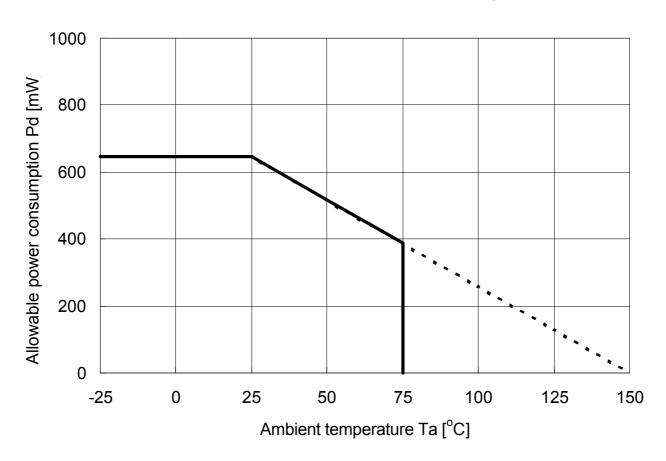


ABSOLUTE MAXIMUM RATINGS

(Ta = 25°C, unless otherwise noted)

Parameter	Symbol	Ratings	Unit	Note
Supply Voltage 1	Vcc	6.0	V	
Power Consumption	Pd	624	mW	
Operating Temperature	Topr	-20 to +75	°C	
Storage Temperature	Tstg	-40 to +150	°C	

Temperature characteristics (maximum ratings)





M52768FP

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ELECTRICAL CHARACTERISTICS

VIF Section

(Vcc=5V,Ta=25°C unless otherwise noted)

				T ,	lanut		Measurement	Limits				
No.	Parameter	Symbol	Test Circuit	Test Point	Input Point	Input SG	switches set to position 1 unless otherwise noted	MIN	TYP	MAX	Unit	Note
1	Circuit Current	Icc	1	Α	-	-	SW4=2		33		mΑ	
2	Video Output Voltage 8	Vo det8	1	TP8	VIF IN	SG1			1.1		Vp-p	
3	Video Output Voltage 1	Vo det	1	TP1A	VIF IN	SG1			2.0		Vp-p	
4	Video S/N	Video S/N	1	TP1B	VIF IN	SG2	SW1=2		56		dB	1
5	Video Band Width	BW	1	TP1A	VIF IN	SG3	SW19=2 V19=Variable		6.0		MHz	2
6	Input Sensitivity	VIN MIN	1	TP1A	VIF IN	SG4			48		dΒμ	3
7	Maximum Allowable Input	VIN MAX	1	TP1A	VIF IN	SG5			110		dΒμ	4
8	AGC Control Range Input	GR	-	-	-	-			62		dB	5
9	IF AGC Voltage 1	V19	1	TP19	VIF IN	SG6			3.1		V	
10	IF AGC Voltage 2	V2	1	TP2	VIF IN	SG6			3.1		V	
11	Maximum RF AGC Voltage	V13H	1	TP13	VIF IN	SG6			4.75		V	
12	Minimum RF AGC Voltage	V13L	1	TP13	VIF IN	SG7			0.1		٧	
13	RF AGC Delay Point	V13	1	TP13	VIF IN	SG8			93		dΒμ	6
14	Capture Range U	CL-U	1	TP1A	VIF IN	SG9			1.5		MHz	7
15	Capture Range L	CL-L	1	TP1A	VIF IN	SG9			1.8		MHz	8
16	Capture Range T	CL-T	1	-	-	-			3.3		MHz	9



MITSUBISHI ICs (TV)

M52768FP

PLL-INTER VIF/SIF

			Test	Test	Input	Innut	Measurement	Limits		}		
No.	Parameter	Symbol	Circuit	l	Point	Input SG	switches set to position 1 unless otherwise noted	MIN	TYP	MAX	Unit	Note
17	AFT Sensitivity	μ	1	TP14	VIF IN	SG10			30		mV/ kHz	10
18	AFT Maximum Voltage	V14H	1	TP14	VIF IN	SG10			4.8		V	10
19	AFT Minimum Voltage	V14L	1	TP14	VIF IN	SG10			0.1		V	10
20	AFT defeat	AFT def 1	1	TP14	VIF IN	-			2.5		V	
21	Inter Modulation	IM	1	TP1A	VIF IN	SG11	SW19=2 V19=Variable		40		dB	11
22	Differential Gain	DG	1	TP1A	VIF IN	SG12			2		%	
23	Differential Phase	DP	1	TP1A	VIF IN	SG12			2		deg	
24	Sync. tip level	V1 SYNC	1	TP1A	VIF IN	SG2			0.8		V	



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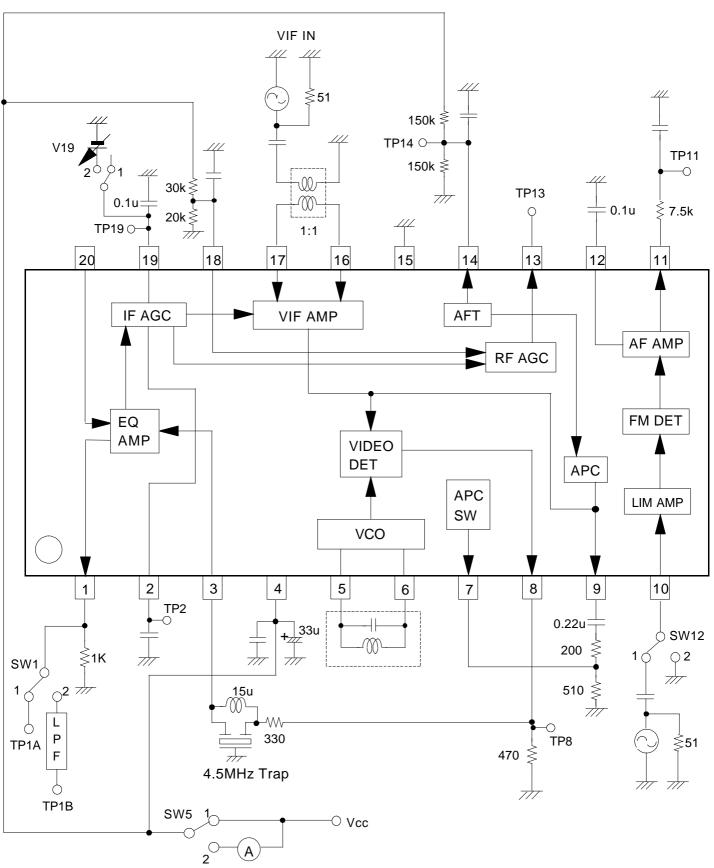
SIF Section

(Vcc=5V,Ta=25°C unless otherwise noted)

		Test		Test	Input	Input	Measurement	Limits				
No.	Parameter	Symbol	Circuit		-		switches set to position 1 unless otherwise noted	MIN	TYP	MAX	Unit	Note
25	AF Output	VoAF 1	1	TP11	SIF IN	SG16			700		mVrms	
26	AFOutput Distortion	THD AF 1	1	TP11	SIF IN	SG16			0.8		%	
27	Limiting Sensitivity	LIM 1	1	TP11	SIF IN	SG17			42		dΒμ	12
28	AM Rejection	AMR 1	1	TP11	SIF IN	SG18			55		dB	13
29	AF S/N	AF S/N 1	1	TP11	SIF IN	SG19			62		dB	14



Measuring Circuit Diagram



Note) All the capacitors are $0.01\mu F$, unless otherwise noted. The Measuring Circuit 1 is Mitsubishi standard evaluation fixture.



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INPUT SIGNAL

SG	50Ω Termination
1	fo = 45.75 MHz AM 20 KHz 77.8 % 90 dBµ
2	fo = 45.75 MHz 90 dBµ Cw
3	f1 = 45.75 MHz 90 dBμ Cw f2 = Frequency Variable 70 dBμ Cw
4	fo = 45.75 MHz AM 20 KHz 77.8% Level Variable
5	fo = 45.75 MHz AM 20 KHz 14.0% Level Variable
6	f0= 45.75 MHz 80 dBµ Cw
7	f0 = 45.75 MHz 110 dBμ Cw
8	f0 = 45.75 MHz Cw Level Variable
9	f0 = Frequency Variable AM 20 KHz 77.8 % 90 dBμ
10	f0 = Frequency Variable 90 dBμ Cw
11	f1 = 45.75 MHz 90 dBμ Cw f2 = 42.17 MHz 80 dBμ Cw f3 = 41.25 MHz 80 dBμ Cw
12	f0 = 45.75 MHz 87.5 % TV modulation Ten-step waveform Sync Tip Level 90 dBµ
13	f1 = 41.25 MHz 95 dBµ Cw
14	f1 = 41.25 MHz 75 dBµ Cw
15	f1 = 45.75 MHz 90 dBµ Cw f2 = 41.25 MHz 70 dBµ Cw
16	fo = 4.5 MHz 90 dBµ FM 400 Hz ±25 KHzdev
17	f0 = 4.5 MHz Level Variable FM 400Hz ±25KHzdev
18	fo = 4.5 MHz 90 dBµ AM 400 Hz 30 %
19	f0 = 4.5 MHz 90 dBµ Cw
20	f0 = 4.5 MHz Level Variable Cw



Notes

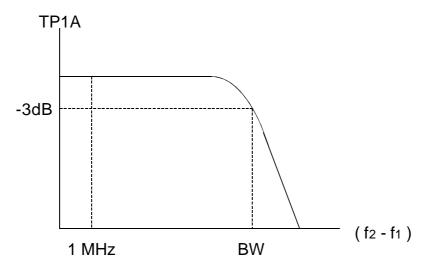
1. Video S/N

Input SG2 to VIF IN and measure the video out(Pin 1) noise in r.m.s at TP1B through a 5MHz (-3dB) L.P.F.

$$S/N=20 \log \left(\frac{0.7 \times Vo \det}{NOISE} \right)$$
 [dB]

2. Video Band Width: BW

- 1. Measure the 1MHz component level of Video output TP1A with a spectrum analyzer when SG3(f2=44.75MHz) is input to VIF IN. At that time, measure the voltage at TP19 with SW19, set to position 2, and then fix V19 at that voltage.
- 2. Reduce f2 and measure the value of (f2-f1) when the (f2-f1) component level reaches -3dB from the 1MHz component level as shown below.



3. Input Sensitivity: VIN MIN

Input SG4 ($Vi=90dB\mu$) to VIF IN , and then gradually reduce Vi and measure the input level when the 20KHz component of Video output TP1A reaches - 3dB from Vo det level.

4. Maximum Allowable Input: VIN MAX

- 1. Input SG5 (Vi=90dB μ) to VIF IN , and measure the level of the 20KHz component of Video output.
- 2. Gradually increase the Vi of SG and measure the input level when the output reaches -3dB.

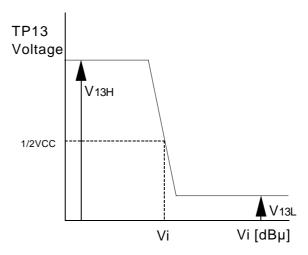


5. AGC Control Range: GR

GR = VIN MAX - VIN MIN [dB]

6. RF AGC Operating Voltage: V13

Input SG8 to VIF IN and gradually reduce Vi and then measure the input level when RF AGC output TP17 reaches 1/2 VCC, as shown below.



7. Capture range: CL - U

- 1. Increase the frequency of SG9 until the VCO is out of locked-oscillation.
- 2. And decrease the frequency of SG9 and measure the frequency fU when the VCO is locked.

$$CL - U = fU - 45.75$$
 [MHz]

8. Capture range: CL - L

- 1. Decrease the frequency of SG9 until the VCO is out of locked-oscillation.
- 2. And increase the frequency of SG9 and measure the frequency fL when the VCO is locked.

$$CL - L = 45.75 - fL$$
 [MHz]

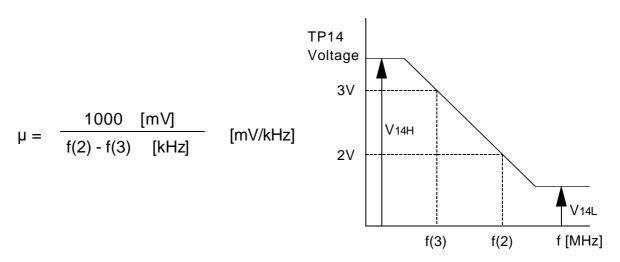
9. Capture range: CL - T

$$CL - T = CL - U + CL - L$$
 [MHz]



10. AFT sensitivity μ, Maximum AFT voltage V14H , Minimum AFT voltage V14L

- 1. Input SG10 to VIF IN, and set the frequency of SG10 so that the voltage of AFT output TP14 is 3[V]. This frequency is named f(3).
- 2. Set the frequency of SG10 so that the AFT output voltage is 2[V]. This frequency is named f(2)
- 3. IN the graph, maximum and minimum DC voltage are V14H and V14L, respectively.



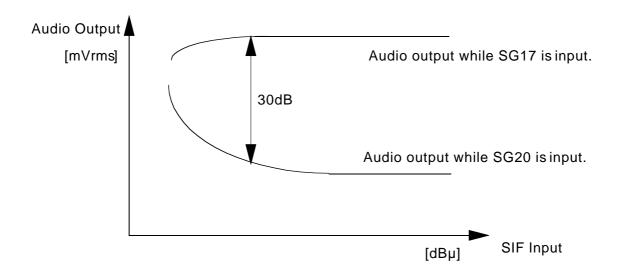
11. Inter modulation: IM

- 1. Input SG11 to VIF IN, and measure video output TP9 with an oscilloscope.
- 2. Adjust AGC filter voltage V19 so that the minimum DC level of the output waveform is Sync. tip level1.5V.
- At this time, measure TP9 with a spectrum analyzer.
 The inter modulation is defined as a difference between 0.92MHz and 3.58 MHz frequency components.



12. Limiting Sensitivity: LIM

- 1. Input SG17 to SIF IN, and measure the 400Hz component level of AF output TP11.
- 2. Input SG20 to SIF IN, and measure the 400Hz component level of AF output TP11.
- 3. The input limiting sensitivity is defined as the input level when a difference between each 400Hz components of audio output (TP11) is 30dB, as shown below.



13. AM Rejection: AMR

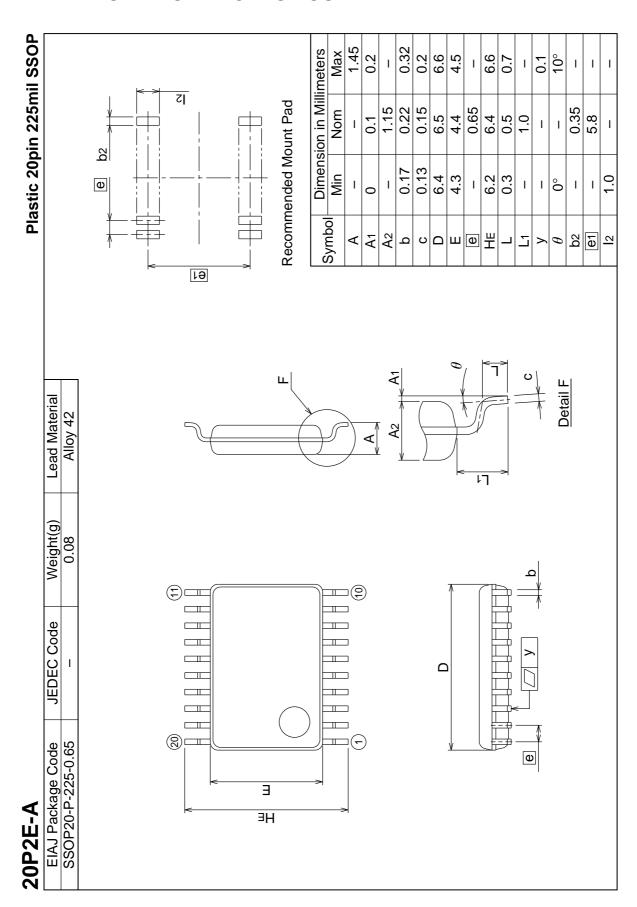
- 1. Input SG18 to SIF IN ,and measure the output level of Audio output (TP11). This level is named VAM.
- 2. AMR is; $AMR = 20log \left(\frac{VoAF (mVr.m.s)}{VAM (mVr.m.s)} \right)$ [dB]

14. AF S/N: AF S/N

- 1. Input SG19 to SIF IN ,and measure the output noise level of Audio output (TP11). This level is named VN.
- 2. S/N is; $S/N = 20log \quad \left(\frac{VoAF (mVr.m.s)}{VN (mVr.m.s)} \right)$ [dB]



DETAILED DIAGRAM OF PACKAGE OUTLINE



PLL-INTER VIF/SIF

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